

**Search Notes**

Application/Control No.

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Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

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Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	7/8/2007	PL
Inventor name search updated EAST/PALM	7/8/2007	PL